Notice of References Cited Application/Control No. O9/878,519 Examiner Nhan T. Tran Applicant(s)/Patent Under Reexamination BEAN ET AL. Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	Α	US-6,567,120	05-2003	Hamamura et al.	348/231.99
	В	US-5,796,428	08-1998	Matsumoto et al.	348/207.99
	C	US-5,805,210	09-1998	Sekiya et al.	348/157
	D	US-4,253,753	03-1981	Takahashi, Akira	396/318
	Е	US-6,226,449	05-2001	Inoue et al.	348/231.5
	F	US-2002/0021362	02-2002	Ejima et al.	348/232
	G	US-2002/0080256	06-2002	Bates et al.	348/344
	Н	US-			
	1	US-			
	J	US-			
	К	US-			
	L	US-			
	М	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	0					
	Р					
	ď					
	R					
	S					
	Т					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	w	
	X	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)

Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.